

General Description

- Trench Power MOSFET Technology
- Low $R_{DS(ON)}$
- Optimized for High Reliable Switch Application
- High Current Capability
- RoHS and Halogen-Free Compliant

Applications

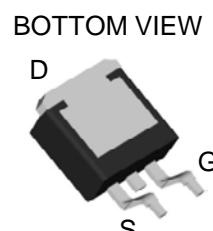
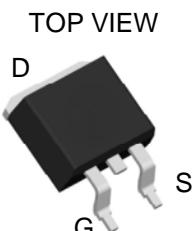
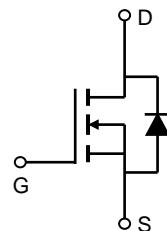
- Motor Drive
- Load Switch
- Battery Protection
- General DC/DC Converters

Product Summary

V_{DS}	30V
I_D (at $V_{GS}=10V$)	183A
$R_{DS(ON)}$ (at $V_{GS}=10V$, typ)	2.3mΩ
$R_{DS(ON)}$ (at $V_{GS}=4.5V$, typ)	2.7mΩ

100% UIS Tested

100% R_G Tested



Orderable Part Number	Package Type	Form	Minimum Order Quantity
VIS30023	TO-263	Tape & Reel	3000

Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V_{DS}	30	V
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current ⁽⁵⁾	I_D	183	A
$T_C=100^\circ C$		116	
Pulsed Drain Current ⁽³⁾	I_{DM}	449	
Continuous Drain Current	I_{DSM}	40	A
$T_A=70^\circ C$		32	
Avalanche Current ⁽³⁾	I_{AS}	65	A
Avalanche energy $L=0.1mH$ ⁽³⁾	E_{AS}	211	mJ
Power Dissipation ⁽²⁾	P_D	140	W
$T_C=100^\circ C$		56.1	
Power Dissipation ⁽¹⁾	P_{DSM}	6.8	W
$T_A=70^\circ C$		4.3	
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150	°C

Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ⁽¹⁾	$R_{\theta JA}$	15.3	18.4	°C/W
Maximum Junction-to-Ambient ^(1,4) Steady-State		67.9	81.5	°C/W
Maximum Junction-to-Case	$R_{\theta JC}$	0.74	0.89	°C/W



VIS30023

30V N-Channel Power Trench MOSFET

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=250\text{mA}, V_{GS}=0\text{V}$	30			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=30\text{V}, V_{GS}=0\text{V}$	$T_J=55^\circ\text{C}$	1	5	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 20\text{V}$			± 100	nA
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\text{mA}$	1.4	1.8	2.2	V
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=20\text{A}$		2.3	2.8	$\text{m}\Omega$
			$T_J=125^\circ\text{C}$	2.5		
		$V_{GS}=4.5\text{V}, I_D=20\text{A}$		2.7	3.3	$\text{m}\Omega$
g_{FS}	Forward Transconductance	$V_{DS}=5\text{V}, I_D=20\text{A}$		120		S
V_{SD}	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.69		V
I_S	Maximum Body-Diode Continuous Current				140	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=15\text{V}, f=1\text{MHz}$		6335		pF
C_{oss}	Output Capacitance			756		pF
C_{rss}	Reverse Transfer Capacitance			367		pF
R_g	Gate resistance	f=1MHz		0.8		Ω
SWITCHING PARAMETERS						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, I_D=20\text{A}$		104		nC
$Q_g(4.5\text{V})$	Total Gate Charge			51		nC
Q_{gs}	Gate Source Charge			15		nC
Q_{gd}	Gate Drain Charge			18		nC
$t_{\text{D(on)}}$	Turn-On DelayTime	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, R_L=0.75\text{W}, R_{\text{GEN}}=3\text{W}$		8.6		ns
t_r	Turn-On Rise Time			9.6		ns
$t_{\text{D(off)}}$	Turn-Off DelayTime			58.4		ns
t_f	Turn-Off Fall Time			22.8		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=20\text{A}, \text{di/dt}=500\text{A/ms}$		29.3		ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=20\text{A}, \text{di/dt}=500\text{A/ms}$		20.5		nC

- 1) $R_{\theta JA}$ is measured with the stand-alone device, without PCB, in a still air environment with $T_A = 25^\circ\text{C}$. The Power dissipation P_{DSM} is based on $R_{\theta JA} \leq 10\text{s}$ and the maximum allowed junction temperature of 150°C . The value in any given application depends on the user's specific board design.
- 2) The power dissipation P_D is based on $T_{J(\text{MAX})}=150^\circ\text{C}$, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.
- 3) Single pulse width limited by junction temperature $T_{J(\text{MAX})}=150^\circ\text{C}$.
- 4) $R_{\theta JA}$ is the sum of the thermal impedance from junction to case $R_{\theta JC}$ and case to ambient.
- 5) The maximum current rating is package limited.

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

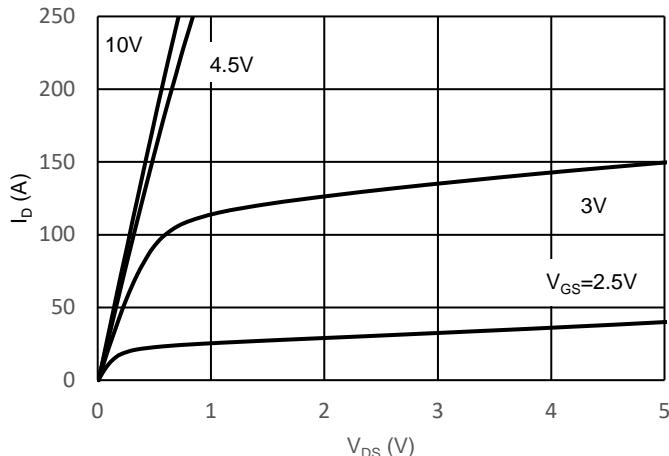


Fig 1. Typical Output Characteristics

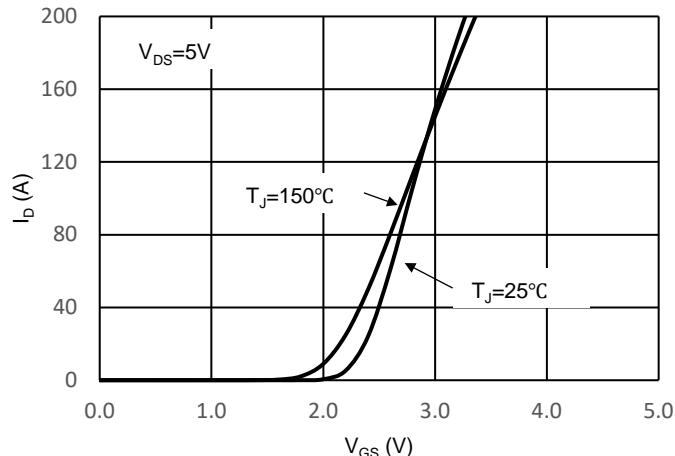


Fig 2. Typical Transfer Characteristics

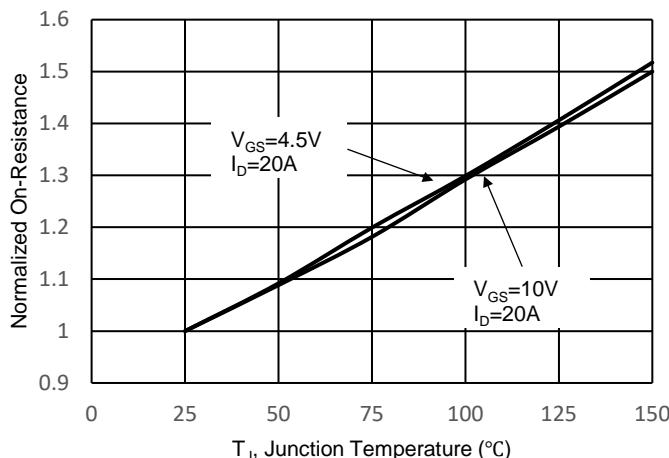


Fig 3. Normalized On-Resistance vs. Temperature

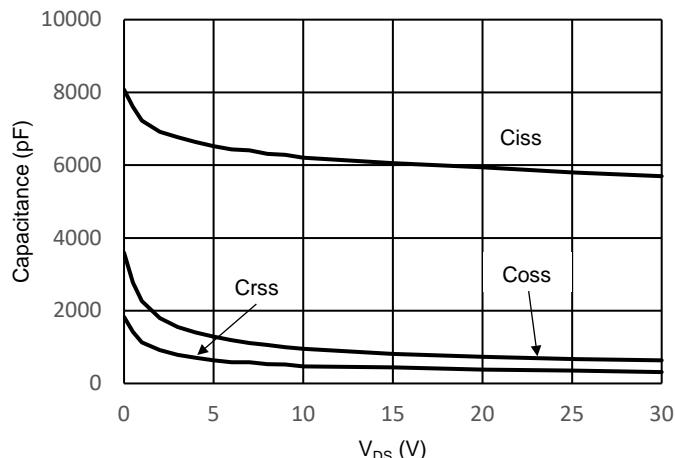


Fig 4. Typical Capacitance vs. V_{DS}

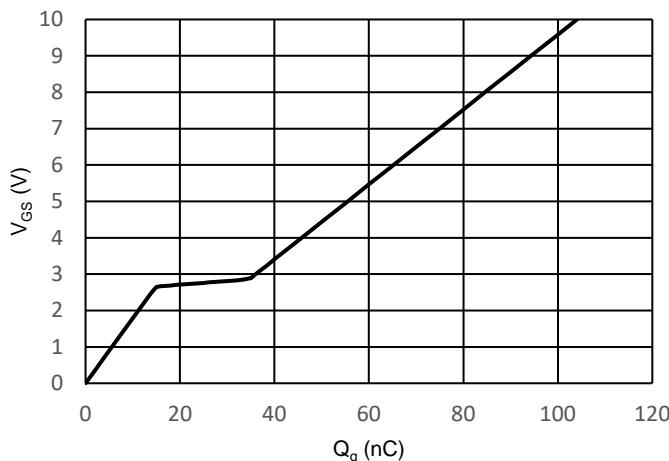


Fig 5. Typical Gate Charge vs. V_{GS}

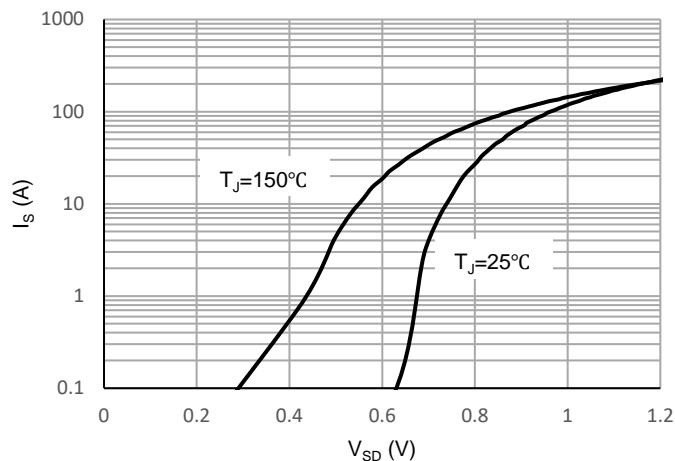
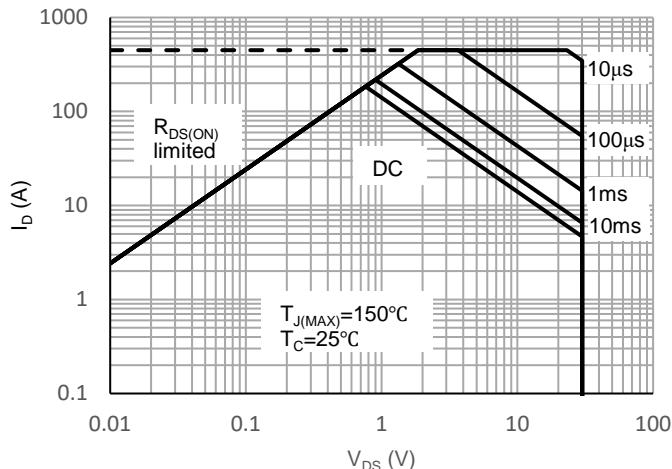
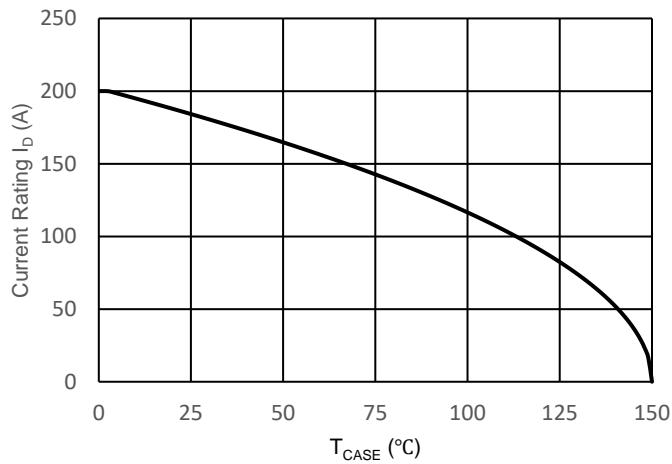
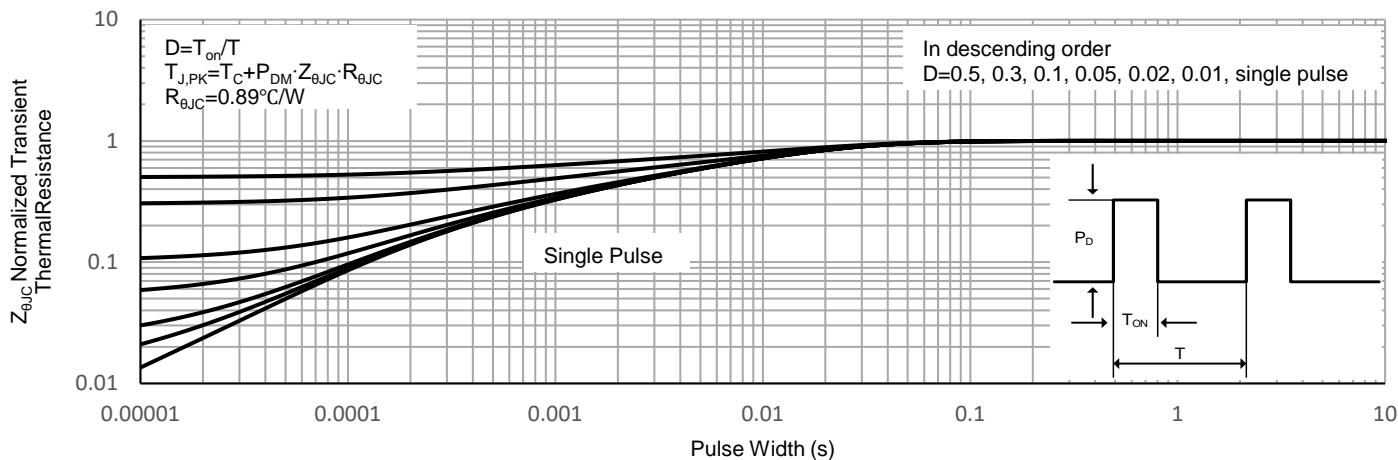
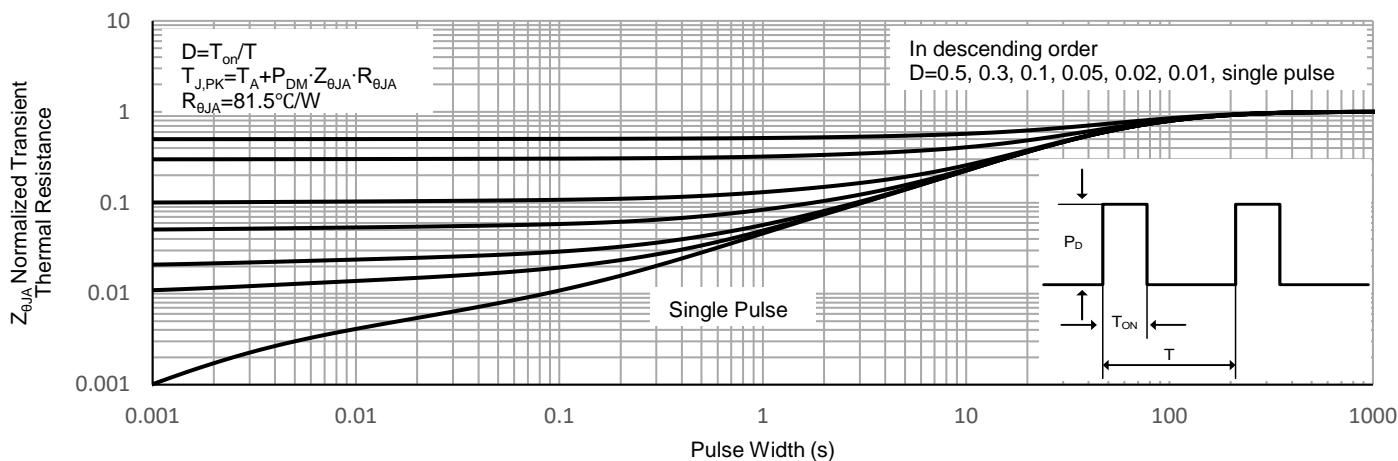
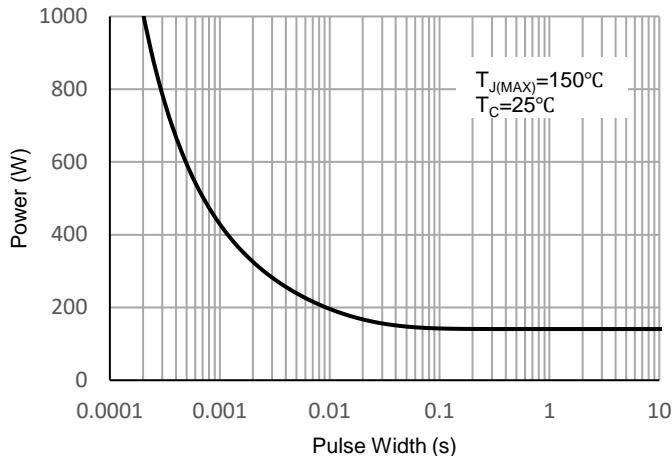
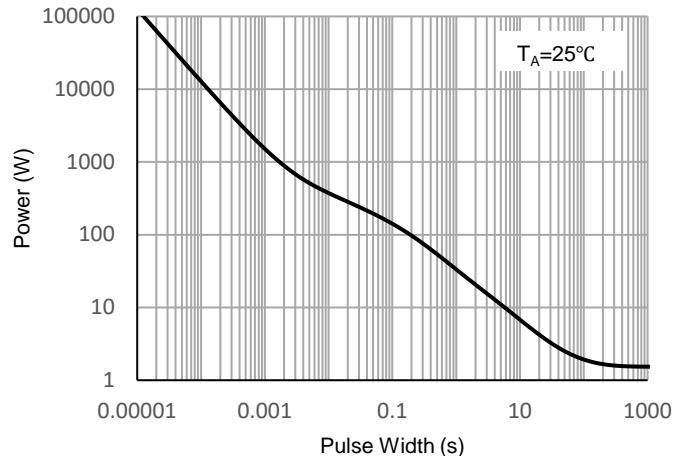
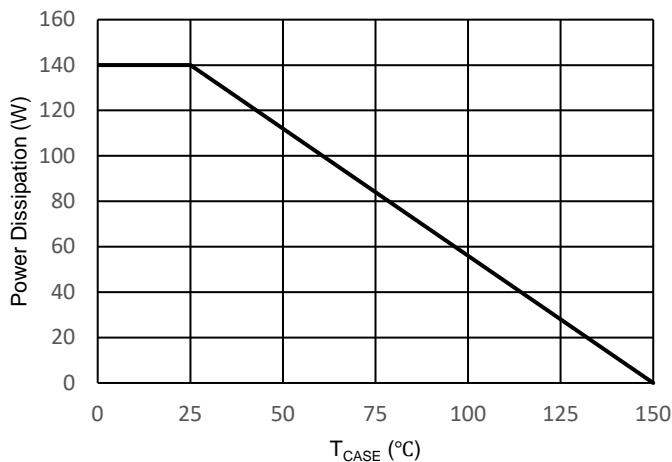
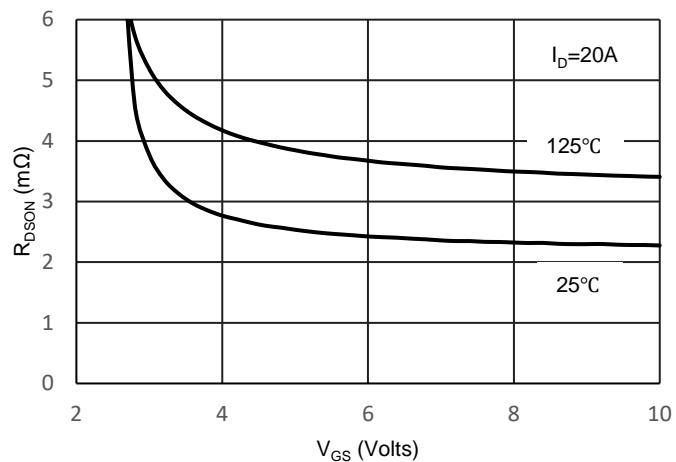
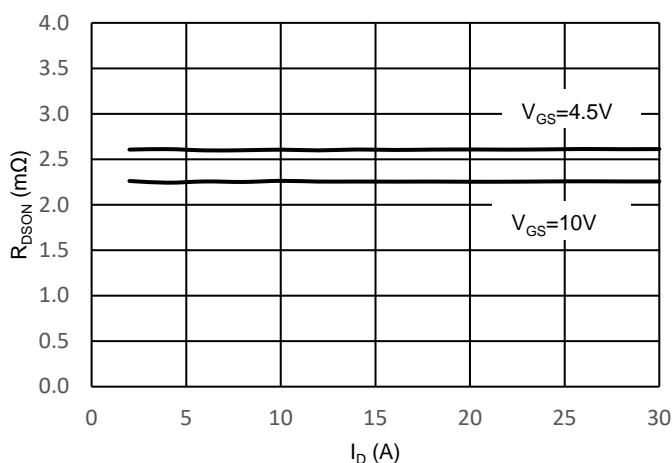
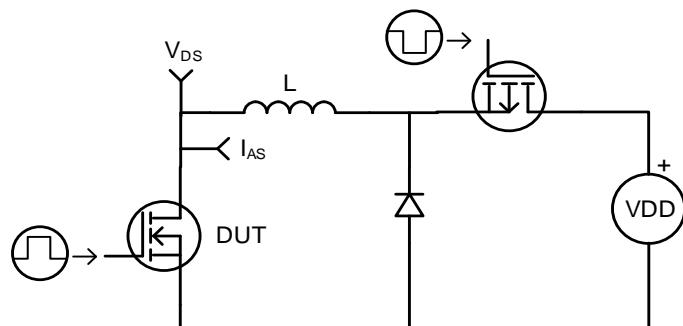
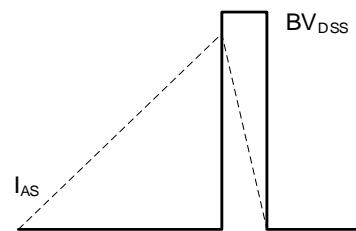
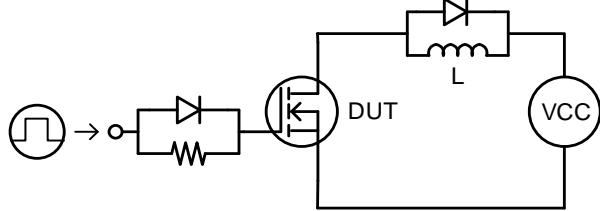
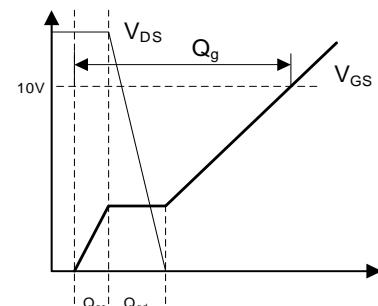
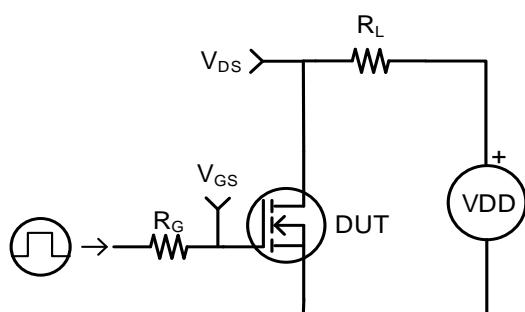
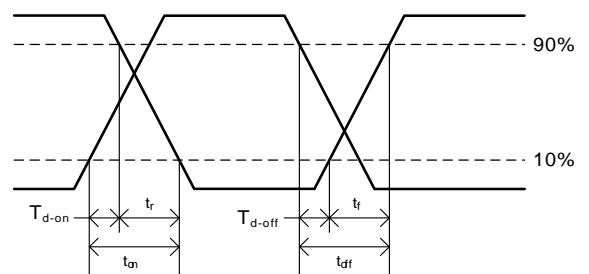
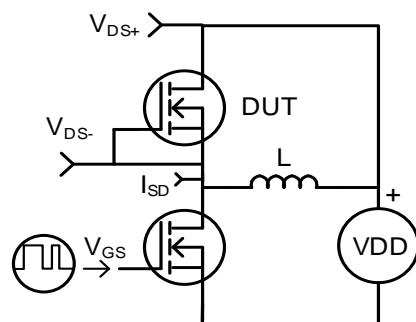
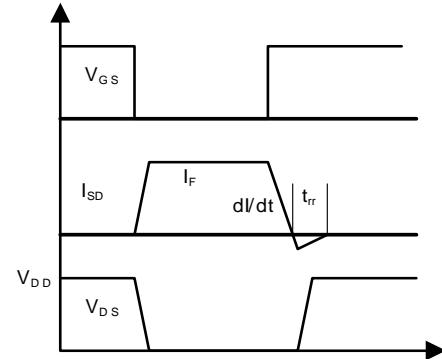
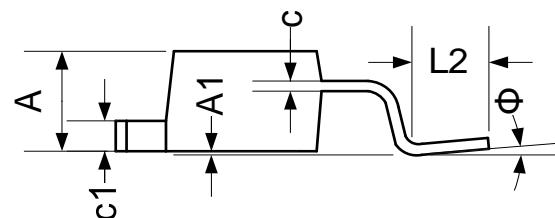
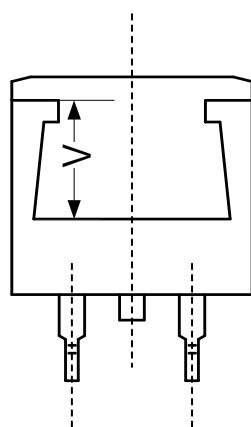
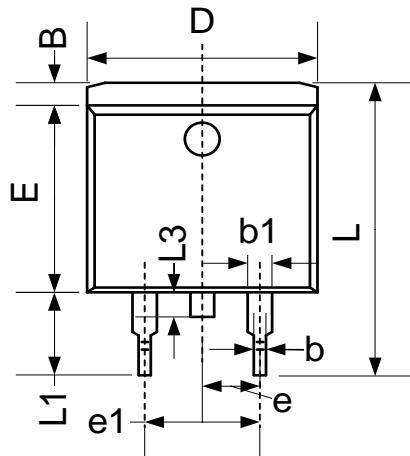


Fig 6. Typical Source-Drain Diode Forward Voltage

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Fig 7. Maximum Safe Operating Area

Fig 8. Maximum Drain Current vs. Case Temperature

Fig 9. Normalized Maximum Transient Thermal Impedance, Junction-to-Case

Fig 10. Normalized Maximum Transient Thermal Impedance, Junction-to-Ambient

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Fig 11. Single Pulse Power Rating Junction-to-Case

Fig 12. Single Pulse Power Rating Junction-to-Ambient

Fig 13. Maximum Power Rating vs. Temperature

Fig 14. Maximum Power Rating vs. V_{GS}

Fig 15. On-Resistance vs. Drain Current

TEST CIRCUIT

Fig16. Unclamped Inductive Test Circuit

Fig17. Unclamped Inductive Waveform

Fig18. Q_g Test Circuit

Fig19. Q_g Waveform

Fig18. Resistive Switching Test Circuit

Fig19. Switching Time Waveform

TEST CIRCUIT

Fig20. Diode Recovery Test Circuit

Fig21. Diode Recovery Test Waveform


SYMBOL	MILLIMETERS	
	MIN [mm]	MAX [mm]
A	4.470	4.670
A1	0.000	0.150
B	1.120	1.420
b	0.710	0.910
b1	1.170	1.370
c	0.310	0.530
c1	1.170	1.370
D	10.010	10.310
E	8.500	8.900
e	2.540 TYP.	
e1	4.980	5.180
L	14.940	15.500
L1	4.950	5.450
L2	2.340	2.740
L3	1.300	1.700
Φ	0°	8°
V	5.600 REF.	